Sear	ch Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/647,107	ISHIDA ET AL.	
Examiner	Art Unit	
Jim Vannucci	2828	

	SEARCHED		
Class	Subclass	Date	Examiner
			-
			<u>-</u>
			<u> </u>
-			

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
:			

SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)
	DATE	EXMR
fluorescent, semiconductor, particles	8/17/2005	JV